

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2493		PRIORITY SERIAL NO. 09/521,092	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Scott E. Moore et al.			
IDS received on 04/07/2004				PRIORITY FILING DATE March 7, 2000		PRIORITY GROUP 3723	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	5,836,805	Obeng				
	AB	6,066,030	Uzoh				
	AC	6,077,147	Yang et al.				
	AD	6,048,256	Obeng et al.				
	AE	5,718,620	Tanaka et al.				
	AF	5,885,134	Shibata et al.				
	AG	6,099,386	Tsai et al.				
	AH	6,159,082	Sugiyama et al.				
	AI	6,165,048	Mass et al.				
	AJ	6,183,352	Kurisan				
	AK	5,653,624	Ishikawa et al.				
	AL	5,923,433	Giaffre et al.				
	AM	6,136,043	Robinson et al.				
	AN	6,482,325 B1	Corlett et al.				
	AO	6,379,538 B1	Corlett et al.				
	AP	5,755,614	Adams et al.				
	AQ	5,664,990	Adams et al.				
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AR						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AS						
EXAMINER /Roy M. Punnoose/				DATE CONSIDERED 01/15/2009			
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M122-2493		PRIORITY SERIAL NO. 09521,092	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Scott E. Moore et al.			
					PRIORITY FILING DATE March 7, 2000		PRIORITY GROUP 3723	
U.S. PATENT DOCUMENTS								
*Examine Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
		AA						
		AB						
		AC						
		AC						
		AC						
		AC						
		AE						
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
		AH						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AJ	<i>"The Science and Engineering of Microelectronic Fabrication," Campbell, Stephen A.; Oxford University Press; 1996; pp. 253-257.</i>						
	AI	http://www.intertechnology.com/html/sensors.htm , Inter Technology, Sensors, 03/25/99, 2 pages						
	AJ	http://www.fhsinc.com/complete/usaita/m/tite.htm , FTS, <i>Analite-SDI Turbidity Sensor</i> , 03/25/99, 1 page						
	AK	http://www.customsensors.com/oplmax.htm , Custom Sensors & Technology, <i>OptiMax 6000 Series Process Photometric Analyzers</i> , 03/25/99, 2 pages						
	AL	http://www.reflectronics.com/reflectronics_inc_consens.htm , Reflectronics, Inc., <i>Fiber Optic Backscatter Sensor</i> , 03/25/99, 1 page						
	AM	http://www.honeywell.com/sensing/prodinfo/turbidity/technical/turbidity.at , Gary O'Brien, Honeywell, <i>Turbidity Sensor for Electromechanical Dishwasher Control</i> , 1998-1999, 11 pages						
	AT	http://www.impomat.com/O_automa/1097O064.htm , ARB Instrumentation, <i>The Stockroom, Photodiode Sensor</i> , 1999, 1 page						
EXAMINER				/Roy M. Punnoose/				
				DATE CONSIDERED 01/15/2009				
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